Part 7

Model selection

ST740

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Model selection

- We now have many potential models in our arsenal
- For a given dataset, how do determine whether a simple model is sufficient or if we need to bring out the "big guns"?
- Is there a "right" model? Probably not
- A statistical model is a mathematical representation of the system that includes errors and biases in the observation process
- All models are simplifications of reality
- Why fit models at all?
- We want a model that is as simple as possible yet seems to fit the data reasonably well

Outline

Model selection



Model averaging

Selection criteria

Cross validation
 Model evaluation

Measures of fit



Bayes factors (BF)

- In some sense BFs are the gold standard
- Say we are comparing two models, M_1 and M_2
- For example, $Y \sim \text{Binomial}(n, \theta)$ and the two models are

 $\mathcal{M}_1: \theta = 0.5$ and $\mathcal{M}_2: \theta \neq 0.5$

• Another example, $Y_1, Y_2, ..., Y_n$ is a time series and

 \mathcal{M}_1 : Cor $(Y_{t+1}, Y_t) = 0$ and \mathcal{M}_2 : Cor $(Y_{t+1}, Y_t) > 0$

Another example,

 \mathcal{M}_1 : E(Y) = $\beta_0 + \beta_1 X$ and \mathcal{M}_2 : E(Y) = $\beta_0 + \beta_1 X + \beta_2 X^2$

Bayes factors (BF)

- This is really the same as hypothesis testing, and in fact Bayes factors are the gold standard for hypothesis testing
- As before we proceed by computing the posterior probability of the two models
- This require priors probabilities $p(M_1)$ and $p(M_2)$
- > This is not prior on a parameter, it is a prior on the model!
- This approach permits statements such "Given the data we have observed, the quadratic model is 5 times more likely than a linear model"

Bayes factors (BF)

The Bayes factor for model 2 compared to model 1 is

$$BF = \frac{\text{Posterior odds}}{\text{Prior odds}} = \frac{p(\mathcal{M}_2|\mathbf{Y})/p(\mathcal{M}_1|\mathbf{Y})}{p(\mathcal{M}_2)/p(\mathcal{M}_1)} = \frac{p(\mathbf{Y}|\mathcal{M}_2)}{p(\mathbf{Y}|\mathcal{M}_1)}$$

• Rule of thumb: BF > 10 is strong evidence for M_2

• Rule of thumb: BF > 100 is decisive evidence for M_2

In linear regression, BIC approximates the BF comparing a model to the null model

Example

• $Y \sim \text{Binomial}(n, \theta)$ with

 $\mathcal{M}_1: \theta = 0.5$ and $\mathcal{M}_2: \theta \neq 0.5$

• $p(Y|M_1)$ is just the binomial density with $\theta = 0.5$

- \mathcal{M}_2 involves an unknown parameter θ
- This requires a prior, say $\theta \sim \text{Beta}(a, b)$, and integration

$$p(Y|\mathcal{M}_2) = \int p(Y,\theta) d\theta = \int p(Y|\theta) p(\theta) d\theta$$

See "BF Beta-binomial" in the online derivations

BF by Y with n = 20 and prior a = 1 and b = 1



BF by Y with n = 20 and prior a = 0.5 and b = 0.5



BF by Y with n = 20 and prior a = 50 and b = 50



BF by Y with n = 20 and prior a = 50 and b = 1



Problems with Bayes factors

 Often hard to compute the required integrals which is only feasible for simple models

Requires proper priors

Can be very sensitive to priors (Lindley's paradox)

In most cases, I prefer computing posterior intervals from the full model and testing by comparing these to the null

Lindley's paradox

- Lindley's paradox is when Bayesian and frequentist hypothesis tests give vastly different results
- For example, Y ~ Normal(μ, σ²) with H_o : μ = 0 versus H_a : μ ≠ 0
- The Bayesian approach requires a prior under H_a, say μ ~ Normal(0, τ²)

▶ Paradox: For any *Y*, Prob($H_0|Y$) → 0 as $\tau \to \infty$

Lindley's paradox

Derivation

Computing Bayes factors using MCMC

- If models can be written as nested, then MCMC can be used to approximate model probabilities
- For example, say

 \mathcal{M}_1 : E(Y) = $\beta_0 + \beta_1 X$ and \mathcal{M}_2 : E(Y) = $\beta_0 + \beta_1 X + \beta_2 X^2$

Both model can be written as

$$\mathsf{E}(Y) = \beta_0 + \beta_1 X + \gamma \beta_2 X^2$$

where $\gamma \in \{0, 1\}$ indicates the model

- The prior on models becomes $\gamma \sim \text{Bernoulli}(0.5)$
- ► Then Prob(γ = 1|Y) = Prob(M₂|Y) can be approximated using MCMC

Stochastic search variable selection (SSVS)

- This is the Bayesian analog of forward/backward/stepwise variable selection
- We place a prior on all 2^p models using p variable inclusion indicators γ_j
- MCMC returns the approximate posterior probability of each model
- With large p all models will have low probability and so this requires long MCMC runs
- As with Bayesian factors, SSVS can be sensitive to priors

Multiple testing

- Bayesian model selection can be extended to multiple tests
- Example: A study measures expression at p genetic markers
- Let θ_j the difference in mean expression for cancer and control subjects for marker j

For
$$j \in \{1, ..., p\}$$
 the hypotheses are

$$\mathcal{M}_{j1}: \theta_j = 0$$
 versus $\mathcal{M}_{j2}: \theta_j \neq 0$

In addition to multiple testing, correlation based on the markers' position on the chromosome is a challenge

Frequentist multiple testing criteria

- Instead of controlling error rates of individual tests, we could consider error rates across all p tests
- Global Type I error is the probability of rejecting any of the *p* tests given θ_j = 0 for all *j* ∈ {1,...,*p*}
- Global Type I error can be controlled via the threshold for the individual tests
- Or we would conduct one global test

A Bayesian global test computes the BF for M₂ versus M₁

Frequentist multiple testing criteria

- In most multiple testing cases, the global null is unrealistic
- False discovery rate (FDR) control is more common
- For a given dataset and testing decision

 $\textit{FDP}(\textbf{Y}) = \frac{\textit{Number of rejections where the null is true}}{\textit{Number of rejections}}$

► For a given testing procedure, its frequentist FDR is

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FDR = E\{P(\mathbf{Y})\}
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where the expectation is wrt ${\boldsymbol{Y}}$

► The testing procedure is tuned (e.g., p-value thresholds are set) so that $FDR \approx \alpha$

Bayesian false discovery rate (BFDR)

• Let $\delta_j = 1$ if the alternative \mathcal{M}_{j2} is true and $\delta_j = 0$ otherwise

- In the Bayesian setting, δ = (δ₁,...,δ_p) is a random variable and MCMC gives its joint posterior distribution
- We use Bayesian decision theory to summarize δ
- Say our decision is $r_j = 1$ if we reject \mathcal{M}_{j1} in favor of \mathcal{M}_{j2}
- The false discovery proportion is

$$FDP(r,\delta) = \frac{\sum_{j=1}^{p} r_j(1-\delta_j)}{\sum_{j=1}^{p} r_j}$$

Bayesian false discovery rate (BFDR

To make the problem tractable, say our decision rule is

$$r_j(t) = \mathcal{I}(\text{reject } \mathcal{M}_{j1} \text{ in favor of } \mathcal{M}_{j2} \text{ if } \pi_j > t),$$

where $\pi_j = \text{Prob}(\delta_j = 1|\text{data}) = \text{Prob}(\mathcal{M}_{j2} = 1|\text{data})$

Given this rule, the FDP is a function only of the threshold t

$$FDP(t,\delta) = \frac{\sum_{j=1}^{p} r_j(t)(1-\delta_j)}{\sum_{j=1}^{p} r_j(t)}$$

Bayesian false discovery rate (BFDR)

- From a Bayesian perspective, the random variable in FDP(t, δ) is δ
- **b** BFDR is the posterior mean $FDP(t, \delta)$

$$BFDR(t) = E_{\delta|Y} \{ FDP(t, \delta) \}$$

- Since this expectation is wrt the joint posterior of δ it accounts for dependence between tests
- We can select *t* so that $BFDR(t) \approx \alpha$
- This controls posterior FDR, not frequentist FDR, although connections can be made ¹

¹ Storey, 2003, The positive false discovery rate: A Bayesian interpretation and the q-value

Outline

Model selection

- Bayes factors
- Model averaging
- Selection criteria
- Cross validation
- Model evaluation
 - Measures of fit
 - Posterior predictive checks

Model averaging

Let's go back to the linear regression example

 \mathcal{M}_1 : E(Y) = $\beta_0 + \beta_1 X$ and \mathcal{M}_2 : E(Y) = $\beta_0 + \beta_1 X + \beta_2 X^2$

- Say we have fit both models and found that both are about equally likely, but that M₁ is slightly preferred
- For prediction, Ŷ, we could simply take the prediction that comes from fitting M₁
- But the prediction from M₂ is likely different and nearly as accurate
- Also, taking the prediction from M₁ suppresses our uncertainty about the form of the model

Model averaging

• Let \hat{Y}_k be the prediction from model \mathcal{M}_k for k = 1, 2

The model averaged predictor is

$$\hat{Y} = w \hat{Y}_1 + (1 - w) \hat{Y}_2$$

- It can be shown that the optimal weight w is the posterior probability of M₁
- Madigan and Raftery² show that BMA gives better prediction than any individual model
- In regression with p predictors, there are 2^p models and all model probabilities will likely be small

²https://www.jstor.org/stable/pdf/2291017.pdf

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Information criteria

- Several information criteria have been proposed that do not require fitting the model several times
- Many are functions of the deviance, i.e., twice the negative log likelihood

$$D(\mathbf{Y}|m{ heta}) = -2\log[f(\mathbf{Y}|m{ heta})]$$

- Ideally, models will have small deviance
- However, if a model is too complex it will have small deviance between be unstable (over-fitting)
- The Akaike information criteria has a complexity penalty

$$\textit{AIC} = \textit{D}(\mathbf{Y}|\hat{\mathbf{ heta}}) + 2p$$

where $\hat{\theta}$ is the MLE

Model with smaller AIC are preferred

Bayesian information criteria (BIC)

The Bayesian information criteria is similar

$$BIC = D(\mathbf{Y}|\hat{\mathbf{ heta}}) + \log(n)p$$

- This is motivated as an approximation to the log Bayes factor of the model compared to the null model
- However, this is only an asymptotic (large n) approximation
- With large n the prior is irrelevant, and so this is not satisfying to a subjective Bayesian

Deviance information criteria (DIC)

- ► DIC is a popular Bayesian analog of AIC or BIC
- Unlike CV, DIC requires only one model fit
- Unlike BF, it can be applied to complex models
- However, proceed with caution
- DIC really only applies when the posterior is approximately normal, and will give misleading results when the posterior far from normality, e.g., bimodal
- DIC is also criticized for selecting overly-complex models

Deviance information criteria (DIC)

- Let $\overline{D} = E[D(Y|\theta)|Y]$ be the posterior mean of the deviance
- Denote $\hat{\theta}$ as the posterior mean of θ
- The effective number of parameters is

$$p_D = ar{D} - D(\mathbf{Y}|\hat{m{ heta}})$$

DIC can be written like AIC,

$$DIC = ar{D} + eta_D = D(\mathbf{Y}|\hat{m{ heta}}) + 2eta_D$$

- Models with small \overline{D} fit the data well
- Models with small p_D are simple
- We prefer models that are simple and fit well, so we select the model with smallest *DIC*

DIC

- The effective number of parameters is a useful measure of model complexity
- ► Intuitively, if there are p parameters and we have uninformative priors then p_D ≈ p
- However, $p_D \ll p$ if there are strong priors
- For example, how many free degrees of freedom do we have with θ ~ Beta(1, 1) versus θ ~ Beta(1000, 1000)?
- In some cases p_D has a nice closed form
- A few examples are worked out in "DIC" on the online derivations

DIC

- As with AIC or BIC, we compute DIC for all models under consideration and select the one with smallest DIC
- Rule of thumb: a difference of *DIC* of less than 5 is not definitive and a difference greater than 10 is substantial
- As with AIC or BIC, the actual value is meaningless, only differences are relevant
- DIC can only be used to compare models with the same likelihood

Watanabe-Akaike information criteria (WAIC)

- WAIC is an alternative to DIC
- It is motivated as an approximation to leave-one-out CV
- In the end WAIC has model-fit and model-complexity components
- It is used the same as DIC with smaller WAIC begin preferred
- In practice the two often give similar results, but WAIC is arguably more theoretically justified

Watanabe-Akaike information criteria (WAIC)

- WAIC is written in terms of the posterior of the likelihood rather than parameters
- Let m_i and v_i be the posterior mean and variance of

 $\log[f(Y_i|\theta)]$

- The effective model size is $p_W = \sum_{i=1}^n v_i$
- The criteria is

$$WAIC = -2\sum_{i=1}^{n} m_i + 2p_W$$

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Cross validation

- Another very common approach is cross-validation
- This is exactly the same procedure used in classical statistics
- This operates under the assumption that the "true" model likely produces better out-of-sample predictions than competing models
- Advantages: Simple, intuitive, and broadly applicable
- Disadvantages: Slow because it requires several model fits and it is hard to say a difference is statistically significant

K-fold Cross validation

- 0 Split the data into *K* equally-sized groups
- 1 Set aside group k as test set and fit the model to the remaining K 1 groups
- 2 Make predictions for the test set *k* based on the model fit to the training data
- 3 Repeat steps 1 and 2 for k = 1, ..., K giving a predicted value \hat{Y}_i for all *n* observations
- 4 Measure prediction accuracy, e.g.,

$$MSE = \frac{1}{n}\sum_{i=1}^{n}(Y_i - \hat{Y}_i)^2$$

Variants

- Usually K is either 5 or 10
- K = n is called "leave-one-out" cross-validation, which is great but slow
- The predicted value \hat{Y}_i can be either the posterior predictive mean or median
- Mean squared error (MSE) can be replaced with Mean absolute deviation

$$MAD = \frac{1}{n} \sum_{i=1}^{n} |Y_i - \hat{Y}_i|$$

Also common to compute Cor(Y_i, Y_i), the average posterior variance and coverage of prediction intervals Measures of fit for point predictions

• Corr
$$(Y_i, \hat{Y}_i)$$

• Corr
$$(Y_i, \hat{Y}_i)^2$$

• Bias:
$$\sum_{i=1}^{n} (\hat{Y}_i - Y_i)/n$$

• MSE:
$$\sum_{i=1}^{n} (\hat{Y}_i - Y_i)^2 / n$$

• MAD:
$$\sum_{i=1}^{n} |\tilde{Y}_i - Y_i|/n$$

where \hat{Y}_i and \tilde{Y}_i are the posterior predictive mean and median

Measures of fit for binary data

• Classification accuracy, $\sum_{i=1}^{n} I(Y_i - \hat{Y}_i)/n$

• True and false positive rates comparing Y_i and \hat{Y}_i

Area under the receiver-operator and precision-recall curves comparing Y_i and p_i

• Brier score,
$$BS = \sum_{i=1}^{n} (Y_i - p_i)^2/n$$

where p_i is the posterior predictive probability that $Y_i = 1$ and $\hat{Y}_i = l(p_i > 0.5)$

Measures of fit for quantiles and intervals

- Coverage of 95% prediction interval, $\sum_{i=1}^{n} I\{I_i < Y_i < u_i\}$
- Interval width $\sum_{i=1}^{n} (u_i I_i)/n$
- Interval score

$$\frac{1}{n}\sum_{i=1}^{n}(u_{i}-l_{i})+\frac{2}{\alpha}\left\{(l_{i}-Y_{i})l(Y_{i}< l_{i})+(Y_{i}-u_{i})l(Y_{i}> u_{i})\right\}$$

• Quantile score $\sum_{i=1}^{n} \rho_{\tau} \{ Y_i - q_i(\tau) \} / n$ for check function

$$ho_{ au}(oldsymbol{e}) = egin{cases} au|oldsymbol{e}| & oldsymbol{e} \geq oldsymbol{0} \ (oldsymbol{1} - au)|oldsymbol{e}| & oldsymbol{e} < oldsymbol{0} \ (oldsymbol{1} - au)|oldsymbol{e}| & oldsymbol{e} < oldsymbol{0} \end{cases}$$

where $q_i(\tau)$ is the τ quantile of the PPD, $l_i = q_i(\alpha/2)$ and $u_i = q_i(1 - \alpha/2)$

Measures of overall fit of the PPD

• The log score, $\sum_{i=1}^{n} \log(\hat{f}_i(Y_i)) / n$

 Probability Integral Transform (PIT) Histogram, i.e., a histogram of

$$PIT_i = \hat{F}_i(Y_i)$$

which should be roughly uniform

Continuous rank probability score (CRPS)

$$\int \{\hat{F}(y) - I(Y_i < y)\}^2 dy$$

where \hat{f} and \hat{F} are the posterior predictive PDF and CDF

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Measures of fit

- ▶ In least squares, fit is measured using (adjusted) R²
- A Bayesian version is proposed in Gelman (2019)

• Let
$$E(Y_i|\theta) = \mu_i(\theta)$$
 and $Var(Y_i|\theta) = \sigma^2(\theta)$

Then

$$R^{2} = \frac{\mathsf{V}\{\mu_{1}(\boldsymbol{\theta}),...,\mu_{n}(\boldsymbol{\theta})\}}{\mathsf{V}\{\mu_{1}(\boldsymbol{\theta}),...,\mu_{n}(\boldsymbol{\theta})\} + \mathsf{M}\{\sigma_{1}^{2}(\boldsymbol{\theta}),...,\sigma_{n}^{2}(\boldsymbol{\theta})\}},$$

where M and V are the sample mean and variance operators, respectively

Mixing over θ gives a posterior distribution of R₂

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Posterior predictive checks

Posterior predictive checks

- After comparing a few models, we settle on the one that seems to fit the best
- Given this model, we then verify it is adequate
- The usual residual checks are appropriate here: qq-plots; added variable plots; etc.
- A uniquely Bayesian diagnostic is the posterior predictive check
- This leads to the Bayesian p-value

Posterior predictive distributions

- Before discussing posterior predictive checks, let's review Bayesian prediction in general
- ► The plug-in approach would fix the parameters θ at the posterior mean $\hat{\theta}$ and then predict $Y_{new} \sim f(y|\hat{\theta})$
- This suppresses uncertainty in θ
- We would like to propagate this uncertainty through to the predictions

Posterior predictive distributions (PPD)

We really want the PPD

$$f(Y_{new}|\mathbf{Y}) = \int f(Y_{new}, \theta|\mathbf{y}) d\theta = \int f(Y_{new}|\theta) f(\theta|\mathbf{y}) d\theta$$

MCMC easily produces draws from this distribution

- To make S draws from the PPD, for each of the S MCMC draws of θ we draw a Y_{new}
- This gives draws from the PPD and clearly accounts for uncertainty in θ.

Posterior predictive checks

- Posterior predictive checks sample many datasets from the PPD with the identical design (same n, same X) as the original data set
- We then define a statistic describing the dataset, e.g.,

$$d(\mathbf{Y}) = \max\{Y_1, ..., Y_n\}$$

- Denote the statistic for the original data set as d₀ and the statistic from simulated data set number s as d_s
- If the model is correct, then d₀ should fall in the middle of the d₁,..., d_S

Posterior predictive checks

A measure of how extreme the observed data is relative to this sampling distribution is the Bayesian p-value

$$p=\frac{1}{S}\sum_{s=1}^{S}I(d_s>d_0)$$

If p is near zero or one the model doesn't fit

This is repeated for several d to give a comprehensive evaluation of model fit